**Qualification data for the release of the 1M RF process 152P1G1012C at ADLK iPD line.**

|  |  |  |  |
| --- | --- | --- | --- |
| Qualification of the IPD 1M RF 152P1G1012X Process at ADLK iPD | | | |
| Test | Conditions | Sample Size | Results |
| Early Life Failure (ELF) | MIL-STD-883, Method 1015  125C, Biased, 48 hrs | 4\*667 | Pass |
| High Temperature Operating Life (HTOL)\* | JESD22-A108,  125°C<Tj<135°C, Biased, 1,000 Hours | 3\*77 | Pass |
| High Temperature Storage Life | JESD22-A103,  150°C, 1000hrs | 2\*77 | Pass |
| Temperature Cycle Testing (TCT)\* | JESD22-A104,  -65/+150C, 500cycles | 3\*77 | Pass |
| Autoclave\* | JESD22-A102  121C, 100%RH, 96 hours | 3\*77 | Pass |
| Solder Heat Resistance (SHR)\* | ADI-0049  MSL leve3 | 3\*11 | Pass |

\* Lots preconditioned to MSL3 conditions\*